

Notice of References Cited	Application/Control No. 10/821,701		Applicant(s)/Patent Under Reexamination MELIDEO, JOHN	
	Examiner JOSEPH T. PHAN		Art Unit 2614	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,069,291 B2	06-2006	Graves et al.	709/201
*	B	US-7,188,175 B1	03-2007	McKeeth, James A.	709/227
*	C	US-7,249,045 B2	07-2007	Lauffer, Randall B.	705/8
*	D	US-7,366,683 B2	04-2008	Altberg et al.	705/14.64
*	E	US-7,424,442 B2	09-2008	Wong et al.	705/14.68
*	F	US-7,428,497 B2	09-2008	Agarwal et al.	705/14.54
*	G	US-7,453,998 B2	11-2008	Jacob et al.	379/114.05
*	H	US-6,108,704	08-2000	Hutton et al.	709/227
*	I	US-7,505,920 B2	03-2009	Agarwal et al.	705/14.73
*	J	US-7,509,428 B2	03-2009	McKeeth, James A.	709/227
*	K	US-7,657,013 B2	02-2010	Lurie et al.	379/114.1
*	L	US-6,938,067	08-2005	Hershenson, Matthew J.	709/202
*	M	US-7,295,836	11-2007	Yach et al.	455/415

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.